CAN-LDO ASIC

Infineon

Target Data Sheet

1 Overview

1.1 Features

- High speed CAN transceiver for data transmission rate up to 1 Mbaud
- 5V very low drop voltage regulator
- Excellent EMC behaviour
- Very low quiescent current voltage regulator, typ. 65µA
- Separate enable/inhibit input for transceiver and voltage regulator
- Power-on and under-voltage reset
- CAN outputs short circuit proof to ground and battery
- Reverse polarity proof
- Over-temperatur protection
- Over-load and short circuit protected
- Wide temperature range

Туре	Ordering Code	Package
TLE 6272	on request	P-DSO-14-14

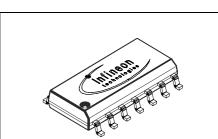
Description

The TLE 6272 is an integration of a high speed CAN-tansceiver functionality together with a low dropout fixed 5V regulator in an enhanced Power P-DSO-14-14 package. The 5V output is designed loads up to 150 mA.

In addition the device offers a reset circuitry as well as separate mode control inputs for the transceiver and the voltage regulator to minimize power consumption. The power-on delay time of the reset feature can be adjusted via a delay input.

By this the TLE 6272 is optimized to support high speed differential mode data transmission in automotive and industrial applications.

The TLE 6272 is designed to withstand the severe conditions of automotive applications.



P-DSO-14-14

version: 1.01 date: 12.05.00

TLE 6272



1.2 Pin Configuration (top view)

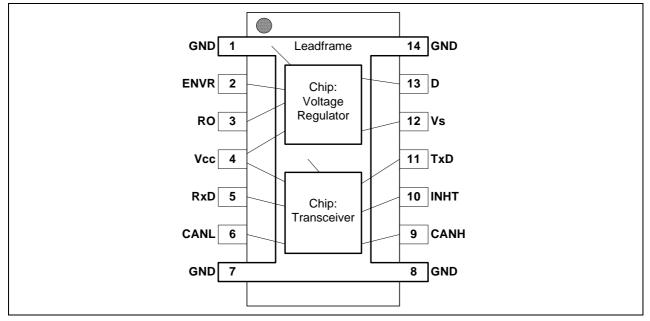


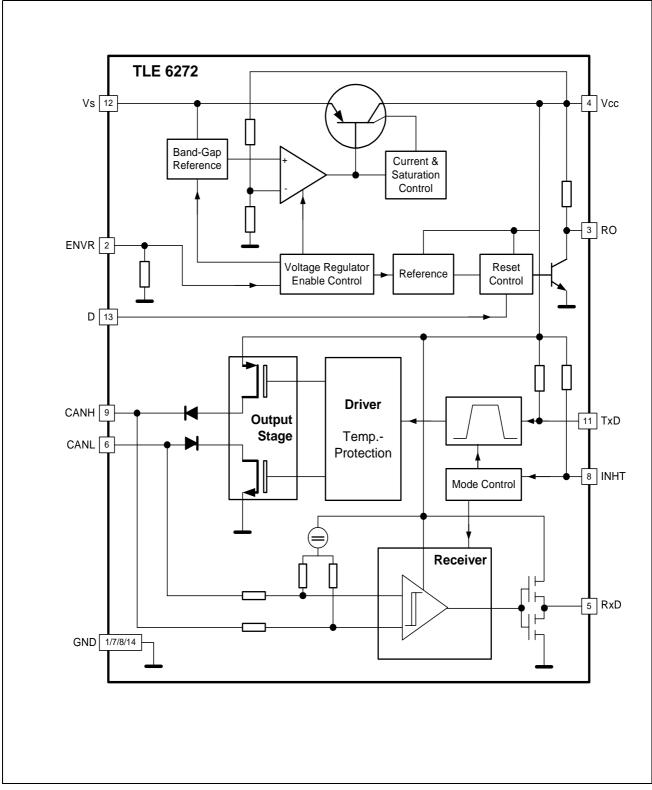
Figure 1

1.3 Pin Definitions and Functions: 5V-version

Pin No.	Symbol	Function
1, 7, 8, 14	GND	Ground; directly connected to chip carrier, place to cooling tabs to improve thermal behaviour
2	ENVR	Enable input voltage regulator; high active, if not needed connect to Vs, 1 M Ω pull down resistor
3	RO	Reset output; open collector output, 20 k Ω pull up
4	V _{CC}	5V Output; connect ot GND with a 22 μ F capacitor, ESR < 3 Ω ,
5	RxD	CAN receive data output; LOW in dominant state
6	CANL	Low line input; LOW in dominant state
9	CANH	High line output; HIGH in dominant state
10	INHT	Inhibit Transceiver; 20 k Ω pull up, set LOW for CAN normal mode
11	TxD	CAN transmit data input; 20 k Ω pull up, LOW in dominant state
12	Vs	Battery supply input; block to ground with ceramic capacitor of 100nF
13	D	Reset Delay; to adjust power-on delay time connect to ground via ceramic capacitor



1.4 Functional Block Diagram







2 Application Information

The TLE 6272 is a dual chip IC that offers features of the CAN-transceiver TLE 6250 and the voltage regulator TLE 4299 in one package.

The voltage regulator of the TLE 6272 is a PNP based very low drop linear voltage regulator. It regulates the output voltage $V_{CC} = 5V$ at an input voltage range of $5.5V \le V_S \le 45V$. The control circuitry protects the device against damages like overcurrent and overtemperature.

The internal control circuit achieves a 5V output voltage with a tolerance of $\pm 2\%$.

The device includes a power-on reset and an under-voltage reset function with adjustable reset delay time. Further there is implemented a separate enable / inhibit function for both, the voltage regulator (including reset circuitry) and the CAN-transceiver. By this the CAN-transceiver circuitry can be switched off to reduce the power consumption while the voltage regulator still supplies other loads. When the voltage regulator is disabled via the ENVR input also the CAN-transceiver is automatically switched off due to the missing supply voltage via V_{CC} .

The reset logic compares the output voltage V_{CC} to an internal threshold. If the output voltage drops below this level, the external reset delay capacitor C_D is discharged. When V_D is lower than V_{st} , the output reset is switched Low . If the output voltage drop is very short, the V_{st} level is not reached and no reset-signal is asserted. This feature avoids resets at short negative spikes at the output voltage e.g. caused by load changes. Please see figure 3, reset timing diagram.

As soon as the output voltage is more positive than the reset threshold, the delay capacitor is charged with constant current. When the voltage reaches V_{DU} the reset output RO is set High again. (Reset-hysteresis)

The reset threshold V_{RT} is internally defined (typical 4.65V). The reset delay time is defined by the external capacitor C_D that is charged by a constant current I_d up to a certain threshold V_{dt} during power on phase. Please see figure 3, reset timing diagram. The reset function is active down to V_{cc} = 1V.

When the INHT is low while V_{CC} is present, the CAN-transceiver circuitry is in the normal operation mode. Then messages can be transmitted or received respectively via the RxD and TxD pin. The CAN stand-by mode is a low power mode that disables both, the receiver as well as the transmitter within the CAN-transceiver.

A message sent by the microcontroller to the TxD input is transformed to a differential mode signal and sent to other CAN nodes via the CANH and CANL output. Differential mode data on the bus lines is reported to the microcontroller via the RxD ouput.



Application description

The input capacitor C_{VS} compenstates line influences. A resistor of approx. 1 Ω in series with C_{VS} , damps the oscillating circuit of input inductivity and input capacitance. The output capacitor C_Q stabilizes the regulating circuit. Stability is guaranteed at values $C_{VCC} \ge 22 \ \mu F$ and an ESR $\le 3 \ \Omega$ within the operating temperature range. Please consider the capacitance-tolerance and temperature coefficient of the reset delay capacitor when calculating the timings.

The reset timing and its calculation is shown in figure 3.



3 Electrical Characteristics

3.1 Absolute Maximum Ratings

Parameter	Symbol	Limit Values		Unit	Remarks
		min.	max.		

Voltages

$V_{ m S}$	- 40	42		
V _{cc}	- 0.3	6.5	V	
I _{cc}	- 5	*)	mA	*) internally limited
V_{ENVR}	- 40	42		
$V_{\mathrm{CANH/L}}$	-20	40	V	
V_1	-0.3	V _{CC} + 0.3	V	$0 V < V_{\rm CC} < 5.5 V$
V_{ESD}	-4	4	kV	human body model (100 pF via 1.5 kΩ)
V_{ESD}	-2	2	kV	human body model (100 pF via 1.5 kΩ)
Tj	- 40	150	°C	
$T_{ m Stg}$	- 50	150	°C	
	V_{CC} I_{CC} V_{ENVR} $V_{CANH/L}$ V_{I} V_{ESD} T_{j}	V_{CC} - 0.3 I_{CC} - 5 V_{ENVR} - 40 $V_{CANH/L}$ -20 V_1 -0.3 V_{ESD} -4 V_{ESD} -2 T_j - 40	V_{CC} - 0.3 6.5 I_{CC} - 5 *) V_{ENVR} - 40 42 $V_{CANH/L}$ -20 40 V_1 -0.3 V_{CC} V_{ESD} -4 4 V_{ESD} -2 2 T_j - 40 150	V_{CC} - 0.3 6.5 V I_{CC} - 5 *) mA V_{ENVR} - 40 42 $V_{CANH/L}$ -20 40 V V_1 -0.3 V_{CC} V V_{ESD} -4 4 kV V_{ESD} -2 2 kV T_j - 40 150 °C

Note: Maximum ratings are absolute ratings; exceeding any one of these values may cause irreversible damage to the integrated circuit.



3.2 Operating Range

Parameter	Symbol	Limit Values		Limit Values		Limit Values		Limit Values		Limit Values		Limit Values		Unit	Remarks
		min.	max.												
Supply voltage	Vs	5.5	42	V											
Junction temperature	$T_{\rm j}$	- 40	150	°C	_										

Thermal Resistances

Junction ambient	$R_{ m thj-a}$	—	70	K/W	-

Thermal Shut Down (junction temperature)

Thermal shutdown temp. CAN	$T_{ m jSD,CAN}$	150	190	°C	10°K hysteresis
Thermal shutdown temp. voltage regulator	$T_{\rm jSD,VR}$	150	190	°C	10°K hysteresis



3.3 Electrical Characteristics

 $V_{\rm S}$ = 13.5 V; R_L = 60 Ω ; $V_{\rm ENVR} > V_{\rm ENVR,ON}$; $V_{\rm INHT} < V_{\rm INHT,ON}$; -40 °C < $T_{\rm j}$ < 125 °C; all voltages with respect to ground; positive current flowing into pin; unless otherwise specified.

Parameter	Symbol	Limit Values			Unit	Test Condition
		min.	typ.	max.		

Current Consumption

Current consumption $(I_q + I_{TR}) = I_S - I_{LOAD}$	$I_q + I_{TR}$		6	10	mA	$\label{eq:linear} \begin{array}{l} I_{CC} \leq 1mA; \\ CAN \ recessive \ state; \\ V_{TxD} = V_{CC} \end{array}$
Current consumption $(I_q + I_{TR}) = I_S - I_{LOAD}$	$I_q + I_{TR}$		45	70	mA	$ I_{CC} \le 1mA; \\ CAN \text{ dominant state;} \\ V_{TxD} = 0V $
Current consumption $(I_q + I_{TR}) = I_s - I_{LOAD}$	$I_q + I_{TR}$			100	μA	$V_{INHT} > V_{INHT,off}$ $I_{CC} \le 1mA; Tj < 85°C$
Current consumption; $(I_q + I_{TR}) = I_s - I_{LOAD}$	$I_q + I_{TR}$	_	250	700	μA	$V_{INHT} > V_{INHT,off}$ $I_{CC} = 10mA$
Current consumption; $(I_q + I_{TR}) = I_s - I_{LOAD}$	$I_q + I_{TR}$	_	2	8	mA	$V_{INHT} > V_{INHT,off}$ $I_{CC} = 50mA$
Current consumption; $(I_q + I_{TR}) = I_s - I_{LOAD}$	$I_q + I_{TR}$			15	μA	V _{ENVR} < V _{ENVR,off} Tj < 85°C

Voltage Regulator

Output voltage	V _{CC}	4.90	5.00	5.10	V	$\begin{array}{l} 1mA \leq I_{CC} \leq 100mA \\ 6V \leq V_S \leq 16V \end{array}$
Current limit	I _{CC}	150	200	500	mA	$I_{CC} = I_{TR} + I_{LOAD}$
Drop voltage	V _{dr}	_	0.25	0.5	V	I _{CC} = 100mA *)
Load regulation	ΔV_{CC}	_	10	30	mV	$1mA \leq I_{CC} \leq 100mA$
Line regulation	ΔV_{CC}	-	10	40	mV	$V_{S} = 6V$ to 26V $I_{CC} = 1mA$
Power Supply Ripple rejection	PSRR	_	50	_	dB	fr= 100Hz; $Vr = 0,5 V_{PP};$ guaranteed by design

*) Drop voltage = $V_S - V_{CC}$ (measured when the output voltage has dropped 100 mV from the nominal value obtained at 13.5 V input.)



 $V_{\rm S}$ = 13.5 V; R_L = 60 Ω ; $V_{\rm ENVR} > V_{\rm ENVR,ON}$; $V_{\rm INHT} < V_{\rm INHT,ON}$; -40 °C < $T_{\rm j}$ < 125 °C; all voltages with respect to ground; positive current flowing into pin; unless otherwise specified.

Parameter	Symbol	Limit Values			Unit	Test Condition
		min.	typ.	max.		

Enable Voltage Regulator ENVR

Enable VR OFF voltage	V _{ENVR, off}			1.5	V	
Enable VR ON voltage	V _{ENVR,on}	4.0			V	
Pull down resistor	R _{ENVR}	0.8	1	1.2	MΩ	

Reset Generator

V _{rt}	4.50	4.65	4.80	V	
R _{RO}	10	20	40	kΩ	
V _R	-	0.1	0.4	V	V _{CC} < 4.5V,
I _R		tbd		μA	V _{RO(Low)} < 400 mV, Reset operational down to 1V
V _{dt}	1.4	1.8	2.2	V	
V _{st}	0.3	0.45	0.60	V	
V _D	-		0.1	V	$V_{CC} < V_{RT}$
I _d	3.0	6.5	9.5	μA	V _D = 1V
<i>t</i> _d	17	28	-	ms	C _D = 100nF
t _{rr}	-	1	-	μs	C _D = 100nF
V _{re}	1.26	1.35	1.44	V	V _{CC} > 3.5V
	$ \begin{array}{c c} R_{RO} \\ \hline R_{RO} \\ \hline V_R \\ \hline I_R \\ \hline V_{dt} \\ \hline V_{st} \\ \hline V_D \\ \hline I_d \\ \hline t_d \\ \hline t_{rr} \\ \end{array} $	$\begin{array}{c c c c c c c c c c c c c c c c c c c $	n 10 20 R_{RO} 10 20 V_R $-$ 0.1 I_R tbd V_{dt} 1.4 1.8 V_{dt} 0.3 0.45 V_D $ I_d$ 3.0 6.5 t_d 17 28 t_{rr} $-$ 1	R_{RO} 10 20 40 V_R - 0.1 0.4 I_R tbd V_{dt} 1.4 1.8 2.2 V_{dt} 0.3 0.45 0.60 V_D - 0.1 0.1 I_d 3.0 6.5 9.5 t_d 17 28 - $t_{\rm rr}$ - 1 -	R_{RO} 10 20 40 kΩ V_R - 0.1 0.4 V I_R tbd μ A V_{dt} 1.4 1.8 2.2 V V_{dt} 0.3 0.45 0.60 V V_{D} - 0.1 V V I_d 3.0 6.5 9.5 μ A t_d 17 28 - ms $t_{\rm rr}$ - 1 - μ s



 $V_{\rm S}$ = 13.5 V; R_L = 60 Ω ; $V_{\rm ENVR} > V_{\rm ENVR,ON}$; $V_{\rm INHT} < V_{\rm INHT,ON}$; -40 °C < $T_{\rm j}$ < 125 °C; all voltages with respect to ground; positive current flowing into pin; unless otherwise specified.

Parameter	Symbol	Lir	nit Valı	Jes	Unit	Test Condition
		min.	typ.	max.		

CAN-Transceiver

Receiver Output R×D

HIGH level output current	I _{RD,H}	-300		μA	$V_{\rm RD}$ > 0.8 x V _{CC} , $V_{\rm diff}$ < 0.4 V *)
LOW level output current	I _{RD,L}	1	2	mA	$V_{\text{RD}} < 0.2 \text{ x V}_{\text{CC}}, V_{\text{diff}} > 1 \text{V}^*)$

Bus receiver

Differential receiver threshold voltage, recessive to dominant edge	V _{diff,d}		0.8	0.9	V	$\begin{array}{l} -20V < (V_{CANH}, V_{CANL}) \\ < 25V \\ V_{diff} = V_{CANH} - V_{CANL} \end{array}$
Differential receiver threshold voltage dominant to recessive edge	V _{diff,r}	0.5	0.6		V	$\begin{array}{l} -20V < (V_{CANH}, V_{CANL}) \\ < 25V \\ V_{diff} = V_{CANH} - V_{CANL} \end{array}$
Differential receiver hysteresis	V _{diff,hys}		200		mV	
CANH, CANL input resistance	R _i		20		kΩ	recessive state
Differential input resistance	<i>R</i> _{diff}		40		kΩ	recessive state

Transmission Input T×D

HIGH level input voltage threshold	V _{TD,H}		2.5	3.5	V	recessive state;
TxD input hysteresis	V _{TD,hys}		100		mV	
LOW level input voltage threshold	V _{TD,L}	1.5	2.4		V	dominant state
HIGH level input current	I _{TD}	-60	-20	-	μΑ	$V_{\text{TxD}} = V_{\text{CC}}$
TxD pull up resistance	R _{TD}	10	20	30	kΩ	



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Parameter	Symbol	Lir	nit Valı	les	Unit	Test Condition
		min.	typ.	max.		

Bus transmitter

CANL/CANH recessive output voltage	V _{CANL/H}	0.4x V _{CC}		0.6x V _{CC}	V	$V_{TxD} = V_{CC}$
CANH, CANL recessive output voltage difference $V_{diff} = V_{CANH} - V_{CANL}$	V _{diff}	-500		50	mV	$V_{TxD} = V_{CC}$; no load
CANL dominant output voltage	V _{CANL}			1.8	V	$V_{TxD} = 0V;$
CANH dominant output voltage	V _{CANH}	2.8			V	V _{TxD} = 0V
CANH, CANL dominant output voltage difference $V_{diff} = V_{CANH} - V_{CANL}$	V _{diff}	1.5		3.0	V	V _{TxD} = 0V;
CANL short circuit current	<i>I</i> _{CANLsc}	50	100		mA	$V_{\text{CANLshort}} = 18V$
			150		mA	$V_{\text{CANLshort}} = 36 \text{V}$
CANH short circuit current	<i>I</i> _{CANHsc}		-110	-50	mA	$V_{\text{CANHshort}} = 0V$
			-120		mA	V _{CANHshort} = - 5V
Leakage current	I _{CANH,lk} I _{CANL,lk}		-80		μA	$V_{CC} = 0V, V_{CANH} = V_{CANL} = -2V$ $T_j < 85^{\circ}C$
Leakage current	I _{CANH,lk} I _{CANL,lk}		280		μA	$V_{CC} = 0V, V_{CANH} = V_{CANL} = 7V$ $T_j < 85^{\circ}C$

Inhibit transceiver input INHT

HIGH level input voltage threshold	V _{INHT,H}		2.5	3.5	V	CAN stand-by mode;
LOW level input voltage threshold	V _{INHT,L}	1.5	2.4		V	CAN normal mode
HIGH level input current	I _{INHT}	-60	-20	-	μA	$V_{\rm INHT} = V_{\rm CC}$
INHT pull up resistance	<i>R</i> _{INHT}	10	20	30	kΩ	



 $V_{\rm S}$ = 13.5 V; R_L = 60 Ω ; $V_{\rm ENVR} > V_{\rm ENVR,ON}$; $V_{\rm INHT} < V_{\rm INHT,ON}$; -40 °C < $T_{\rm j}$ < 125 °C; all voltages with respect to ground; positive current flowing into pin; unless otherwise specified.

Parameter	Symbol	Lir	nit Valı	les	Unit	Test Condition
		min.	typ.	max.		

Dynamic CAN-Transceiver Characteristics

Propagation delay TxD-to-RxD LOW (recessive to dominant)	t _{d(L),TR}	150	280	ns	$C_{\rm L}$ = 47pF; $R_{\rm L}$ = 60 Ω ; $C_{\rm RxD}$ = 20pF
Propagation delay TxD-to-RxD HIGH (dominant to recessive)	<i>t</i> _{d(H),TR}	150	280	ns	$C_{\rm L} = 47 {\rm pF}; R_{\rm L} = 60 \Omega;$ $C_{\rm RxD} = 20 {\rm pF}$
Propagation delay TxD LOW to bus dominant	t _{d(L),T}	100		ns	$C_{\rm L} = 47 {\rm pF}; R_{\rm L} = 60 \Omega;$
Propagation delay TxD HIGH to bus recessive	<i>t</i> _{d(H),T}	100		ns	$C_{\rm L} = 47 {\rm pF}; R_{\rm L} = 60 \Omega;$
Propagation delay bus dominant to RxD LOW	t _{d(L),R}	50		ns	$C_{L} = 47 \text{pF}; R_{L} = 60 \Omega;$ $C_{RxD} = 20 \text{pF}$
Propagation delay bus recessive to RxD HIGH	<i>t</i> _{d(H),R}	50		ns	$C_{L} = 47 \text{pF}; R_{L} = 60\Omega;$ $C_{RxD} = 20 \text{pF}$



4 Diagrams

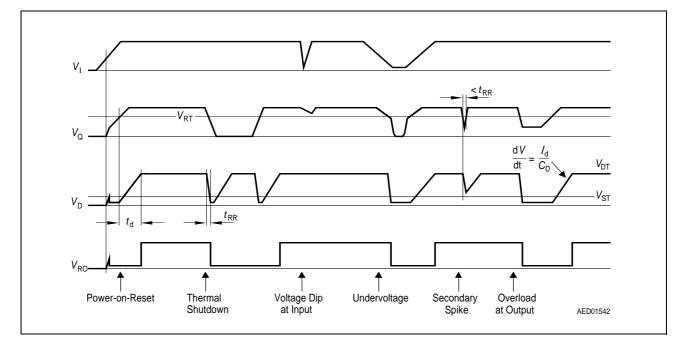


Figure 3: reset timing diagram

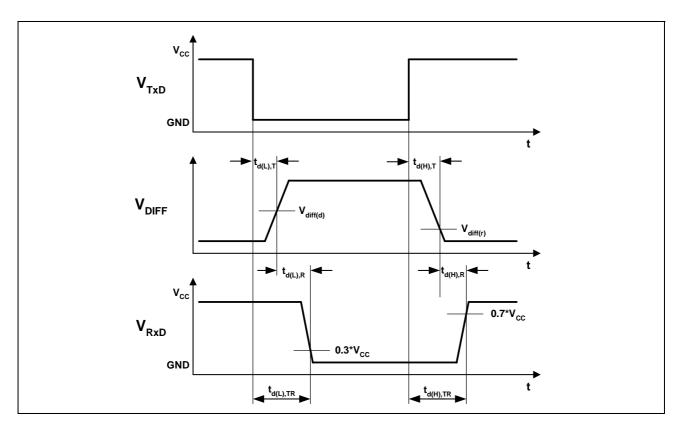


Figure 4: Timing diagrams for dynamic characteristics



5 Application

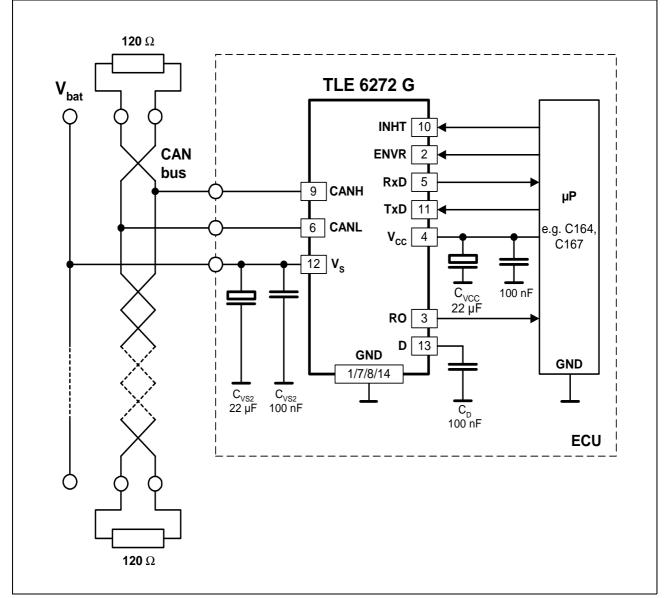
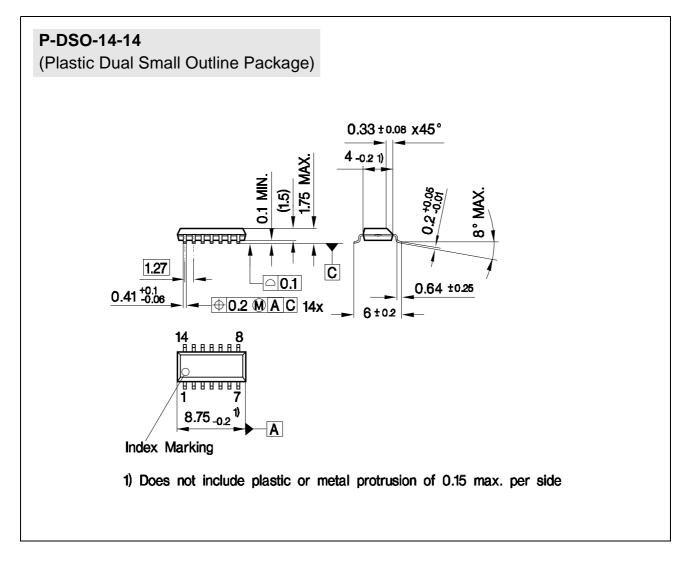


Figure 5 Application Circuit



6 Package Outlines



Sorts of Packing

Package outlines for tubes, trays etc. are contained in our Data Book "Package Information".

SMD = Surface MountedDevice

Dimensions in mm



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